IN THE CLAIMS

Claims 1-9 have been cancelled.

1-9 (Cancelled).

Claim 10 has been amended as follows:

10. An X-ray device as claimed in claim ~~9~~ 11 wherein said measurement arrangement comprises an infrared camera for measuring said temperature.

Add the following new claims:

11. An x-ray device comprising:

an x-ray tube comprising a cathode that emits an electron beam, and an anode that is struck by said electron beam at a focal spot at a focal position to cause x-rays to be emitted from said focal spot;

a deflector that generates a deflection field that interacts with said electron beam in a propagation path between said cathode and said anode to deflect said electron beam to alter said focal spot position;

a temperature measuring arrangement to measure a temperature of said anode and to generate a focal spot position signal dependent on measurement of said temperature of said anode; and

a closed loop regulator connected to said deflector and to said temperature measuring arrangement for regulating said focal spot position in real time during emission of said electron beam, using said deflection field as a controlled variable, dependent on said focal spot position signal as a control variable.

12. A method for operating an x-ray device comprising the steps of:

in an x-ray tube, emitting an electron beam from a cathode onto an anode, said electron beam striking said anode at a focal spot at a focal position, and thereby emitting x-rays from said focal spot;

with an electromagnetic deflector, generating a deflection field to deflect said electron beam in a propagation path between said anode and said anode to alter said focal spot position;

measuring a temperature of said anode and generating a focal spot position signal, indicative of said focal spot position, from the measured temperature; and

regulating generation of said deflection field by said deflector in a closed loop in real time during emission of said electron beam dependent on said focal spot position as a control variable, with said deflection field as a controlled variable.